

IN THE CLAIMS

1. (original) A calibration system for a test system comprising:
a controller for coupling to a plurality of signal sources, wherein said controller is capable of adjusting the timing of an edge output from each of said signal sources;
a plurality of comparators for coupling to a plurality of signal lines coupled to said signal sources, and also coupled to said controller; and
an input line coupler for coupling said plurality of signal lines together by coupling to a socket of said test system, wherein said socket is coupled to said plurality of signal lines.

2. (original) The system of Claim 1, wherein said input line coupler comprises an integrated circuit package for insertion into said socket.

3. (original) The system of Claim 1, wherein said input line coupler comprises a delay compensation line.

4. (original) The system of Claim 3, wherein said input line coupler comprises a silicon substrate.

5. (original) The system of Claim 1, wherein said input line coupler comprises a dielectric substrate.

6. (original) The system of Claim 1, wherein said input line coupler comprises a ball grid array (BGA) package.

7. (original) The system of Claim 1, wherein said input line coupler comprises a leadless chip carrier (LCC).

8. (original) The system of Claim 1, wherein said input line coupler comprises a dual in line package (DIP).

Claims 9-20 (canceled) (restriction/election)